UPCOMING TTTC EVENTS

2007 International Conference on Microelectronic Systems Education (MSE 07)
3–4 June 2007
San Diego, Calif.
http://www.mseconference.org
This conference is dedicated to furthering undergraduate and graduate education in designing and building innovative microelectronic systems.

17th IEEE SW Test Workshop (SWTW 07)
3–6 June 2007
San Diego, Calif.
http://www.swtest.org
SWTW is the only IEEE-sponsored event that focuses on all the activities associated with microelectronic wafer and die-level testing.

13th IEEE International Mixed Signals Testing Workshop (IMSTW 07)
18–20 June 2007
Póvoa de Varzim, Portugal
http://paginas.fe.up.pt/~imstw07
Held in conjunction with the 3rd IEEE International GHz/Gbps Test Workshop (GTW 07), IMSTW is a forum for discussing all aspects of testing, DFT, and reliable design of integrated mixed signals and technologies, functions, and systems.

3rd IEEE International GHz/Gbps Test Workshop (GTW 07)
18–20 June 2007
Póvoa de Varzim, Portugal
http://paginas.fe.up.pt/~gtw07/index.html
The characterization, production testing, and diagnosis of electronic circuits running in the multi-GHz clock range or including I/O capabilities of multi-Gbps data rates poses significant challenges. Held in conjunction with IMSTW, GTW 07 specifically addresses problems and solutions related to ATE and test methodologies concerning issues arising with circuits running at such GHz clock or Gbps data rates.

13th IEEE International On-Line Testing Symposium (IOLTS 07)
9–11 July 2007
Hersonissos-Heraklion, Crete, Greece
http://tima.imag.fr/conferences/IOLTS/IOLTS07/cfp.html
Issues related to online testing are increasingly important in modern electronics systems. In particular, the huge complexity of electronic systems has increased the demand for reliability in several application domains, as well as for low-cost products. There is a corresponding demand for cost-effective online testing techniques. These demands have increased dramatically with the introduction of very deep-submicron and nanometer technologies, which adversely impact noise margins and process parameter variations and which make integrating online testing and fault tolerance mandatory in many modern ICs. IOLTS is an established forum for presenting novel ideas and experimental data on these areas. The symposium also emphasizes online testing in the continuous operation of large applications such as wired, cellular, and satellite telecommunication, as well as secure chips.

NEWSLETTER EDITOR’S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Bruce C. Kim, Dept. of Electrical and Computer Engineering, Univ. of Alabama, 317 Houser Hall, Tuscaloosa, AL 35487-0286; bruce.kim@ieee.org.

Bruce C. Kim
Editor, TTTC Newsletter

BECOME A TTTC MEMBER
For more details and free membership, browse the TTTC Web page: http://tab.computer.org/tttc.